

产品规格书

SPECIFICATIONS FOR PRODUCT

产品类型	TYPE	:	SMD2520
产品规格	SPEC	:	12MHz/2520/10PF/10PPM
产品型号	P/N	:	CJ15-120001010B20
日期	DATE	:	2021/05/06

核准及签名			部バ
R&D APPR.	SIGNATURED		DEPT.
拟制	审核	批准	频率器件事业部
ISSUE	CHECK	APPROVAL	
Ivan	Abbey	Ken	
2021/05/06	2021/05/06	2021/05/06	

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JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO., LTD JSCJ <u>SMCE2520 4pads Crystal Resonator</u>

CJ15-120001010B20

- 1. Scope:
- 1.1 This specification applies to the RoHS/SONY compliance quartz crystal unit with a frequency of 12MHz which will be used in crystal oscillator applications.
- 2. Construction:
- 2.1 Type of Quartz Resonator: SMCE2520 4pads

3. Electrical Characteristics

3.1	Nominal Frequency(f):	12.000MHz
3.2	Load Capacitance(C _L):	10pF
3.3	Frequency Tolerance(\triangle f/f):	±10ppm
3.4	Frequency Temperature Stability:	±20ppm
3.5	Resonance Resistance(ohm):	150ohms Max
3.6	Osc mode:	Fundamental mode
3.7	Shunt Capacitance(C ₀):	<2pF
	Shunt Capacitance(C_0): Drive Level(D_L):	<2pF <100µW
3.8		
3.8 3.9	Drive Level(D _L):	- <100μW
3.8 3.9 3.10	Drive Level(D _L): Operating Temperature Range(T _{OPR}):	<100µW -40 to + 85°C

4. Reliability Specifications

This is the quality control and quality assurance and reliability tests performance data for the RoHS/SONY

compliance 12MHz SMCE2520 4pads crystal resonators

related to the specification and approval sheet provided by JSCJ .

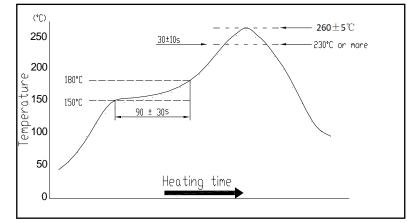
Standard test condition (TEMP.: 20±5°C. Relative humidity: 65±20%)

For any discrepancy in GO/NG, test will be done at TEMP.25±2°C, R.H. 65±5%.

NO.	PROCESS	SPECIFICATION	TEST METHOD
4.1	Temperature Cycle (GB/T 2423.22-2002, Method Nb)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	10 cycles from -55°C to 125°C. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.2	Low Temperature Storage (GB/T 2423.1-2001, Method Aa)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Spending 72 hrs at -55°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.3	High Temperature Storage (GB/T 2423.2-2001, Method Ba)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Spending 72 hrs at 125°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.4	Humidity (GB/T 2423.3- 2006, Method Cab)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Spending 96 hrs at 40 °C \pm 3 °C, with 93 %R.H, Then keep the DUT in dry oven at 40 \pm 5 °C for 24 hour. Measurement taken after DUT being left at room temperature for 1 to 2 hours.
4.5	Vibration (GB/T 2423.10- 1995, Method Fc)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Apply 0.75mm vibration at sweep frequency 10^{\sim} 500 Hz, 10 cycles in each direction of 3 axis. Measurement taken after 1 hour.
4.6	Shock (GB/T 2423.5-1995, Method Ea)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.and exhibit no visible damage.	Peak 1000m/s2, normal width 6ms half sine wave form, 3.7m/s, 3 perpendicular axis of samples, 3 cycles / direction, total 18 cycles. Measurement taken after 1 hour.
4.7	Drop (GB/T 2423.8-1995, Method Ed)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.and exhibit no visible damage.	Free drop to the steel plate with thickness of 3 mm from 1.00 m heights for 3 times.
4.8	Solderability (IEC60068-2- 58,Test Td:)	Terminals shall be covered more then 95% with solder.	Passed through the re-flow oven under the following condition. Preheat 150 to 180° C for 60 to 120sec, and soldering time for $20s \pm 5s$ at 235° C, peak soldering time for $10s \pm 1s$ betweein 240 and 250°C. There is no need to do functional test. 8-12X magnifier.
4.9	Terminal Strength (JIS-C- 6429 Method 1 & 2)	No visible damage	Mount on a glass-epoxy board (100x50x1.6mm), then bend to 2mm displacement (velocity 1mm/sec) and keep for 5 seconds. or pulling force 1.8kg for at least 60 seconds.
4.40		Francisco (t. e. e. e.	Descend through the set fits
4.10	Resistance to Soldering Heat (IEC60068-2-58,Test Td: Table 4)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Passed through the re-flow oven under the following condition. Preheat 150 to 180°C for 60 to 120sec, and sodering time for 60s max at 235°C, peak soldering time for 20s max at 265°C max. Measurement taken after DUT being left at room temperature for at least 2 hours.
4.11	OTHERS		

5. Recommended Reflow soldering condition (SMD) Solder profile

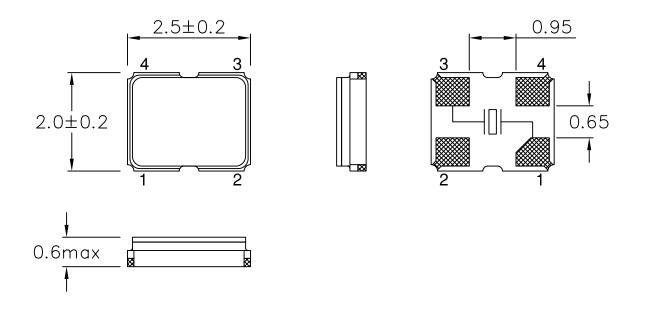
Peak: 260±5°C Soldering zone: 230°C or more, 30±10s. Pre-heating zone 1: 150 \sim 180°C, 90±30s



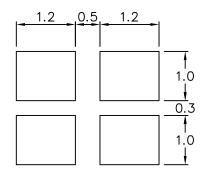
Temperature profile for reflow soldering

6. Soldering iron method

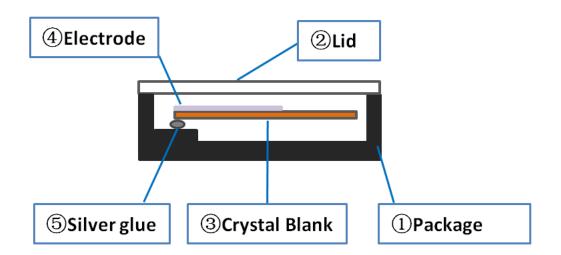
Bit temperature: $350\pm10^{\circ}$ C Application time of soldering iron:3+1 s. For other procedures, refer to IEC 60068-2-20.



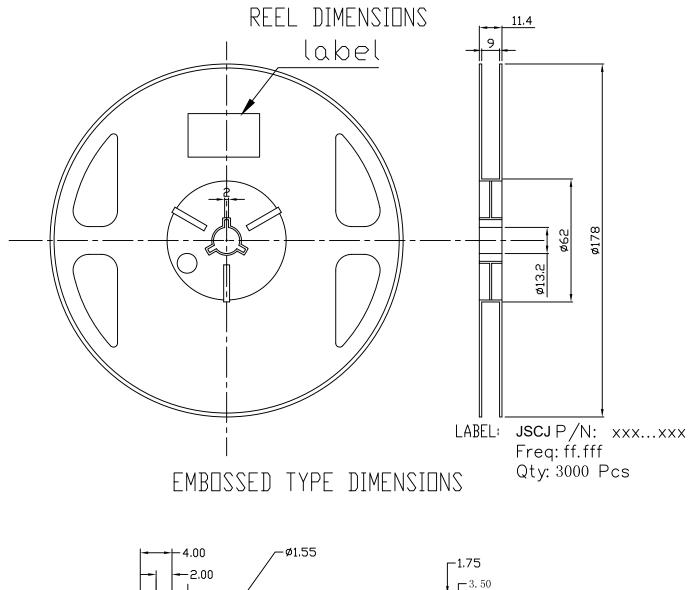
Suggested Pad Layout

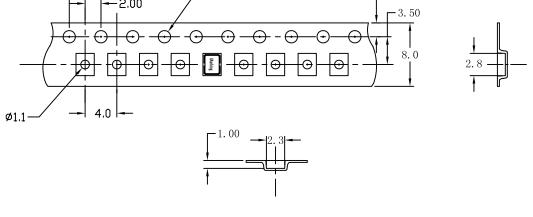


Inside Structure



No.	Components	Materials	
1	Package	Ceramic(Al ₂ O ₃)	
2	Lid	KV(Fe/Ni/Co)	
3	Crystal blank	SiO ₂	
4	Electrode	Ag、 Cr	
5	Silver glue	Ag、CH ₃ OH、SiO ₂	

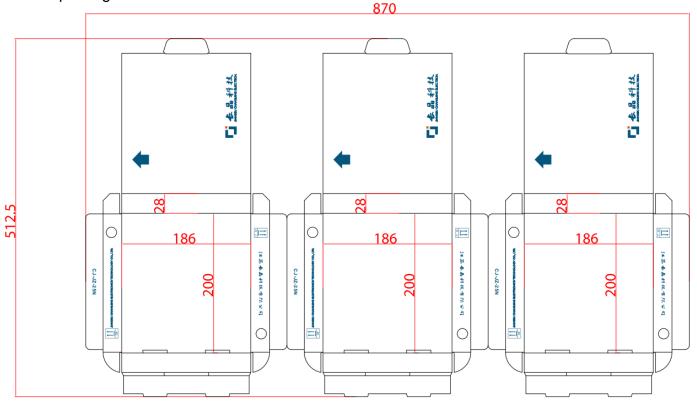




USER FEED DIRECTION

Package

Inside package



Outside package

	◄ 420 mm►	≺ 325 mm ►	≪ 420 mm►	
•— 162.5 mm —•				
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207 mm —	「		Li 本品科技 JANGSU CHANGJING ELEC.TECH.	Г
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